

**Search Notes**

Application/Control No.

10/620,093

Examiner

Phallaka Kik

Applicant(s)/Patent under  
Reexamination

BERTHOLD ET AL.

Art Unit

2825

**SEARCHED**

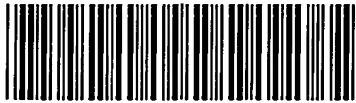
Class	Subclass	Date	Examiner
716	6,13,14	10/17/2005	PK
703	16	10/17/2005	PK
702	79,125	10/17/2005	PK
702	181	10/17/2005	PK
Above	Updated	1/11/2006	PK
Above	Updated	1/19/2006	PK
703	19	1/19/2006	PK
702	118,189	1/19/2006	PK
714	33,700	1/19/2006	PK
714	741	1/19/2006	PK
324	532,535	1/19/2006	PK
324	617,76.54	1/19/2006	PK
324	76.74	1/19/2006	PK

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
716	6,13,14	1/19/2006	PK
703	16,19	1/19/2006	PK
702	79,125	1/19/2006	PK
702/181,118,189; 714/33,700,741 --USPGPUB (see attached)		1/19/2006	PK

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB Class/Sub Searched: 716/1-18; 703/14-16; 702/79,117,125,181 (see attached)	10/17/2005	PK
Above updated search (see attached)	1/11/2006	PK
Consulted with Hal Wachsmann --suggested additional search in 702/118, 189 and possible search in class 714	1/13/2006	PK
Consulted with Kamini Shah --suggested crossed-reference to 703/16,19	1/18/2006	PK
Above updated and new search New cls/sub searched: 703/19; 702/118,189; 714/32-46,724- 745; 324/527-535,537 (see attached)	1/19/2006	PK
New search (con't) 324/603-628,76.54-76.74 (see attached)	1/19/2006	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	10/17/2005	PK
IEE/IEEE Xplore (see attached)	10/17/2005	PK

**Search Notes (continued)**

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